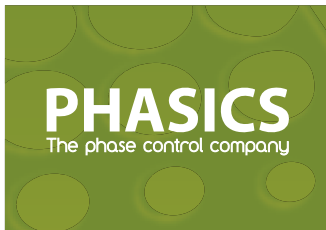
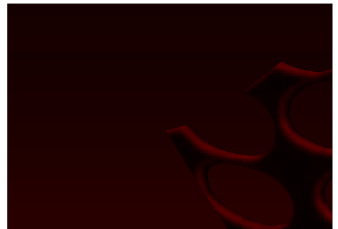
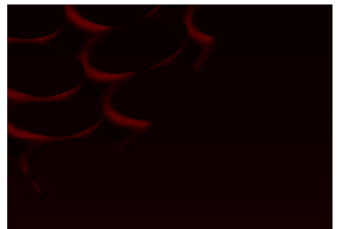
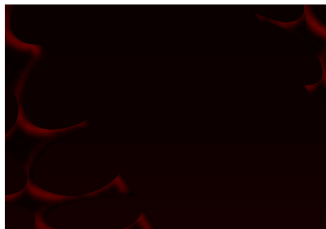
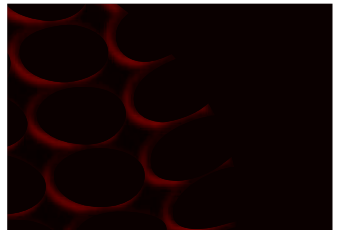
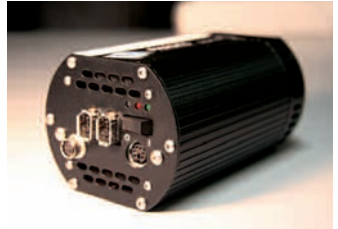
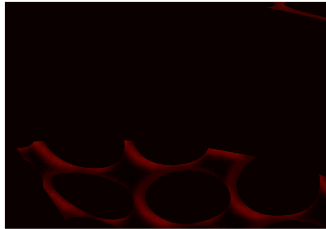
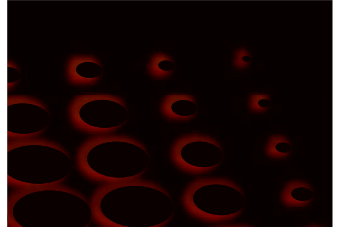
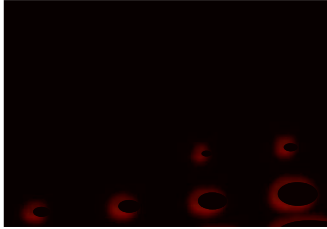
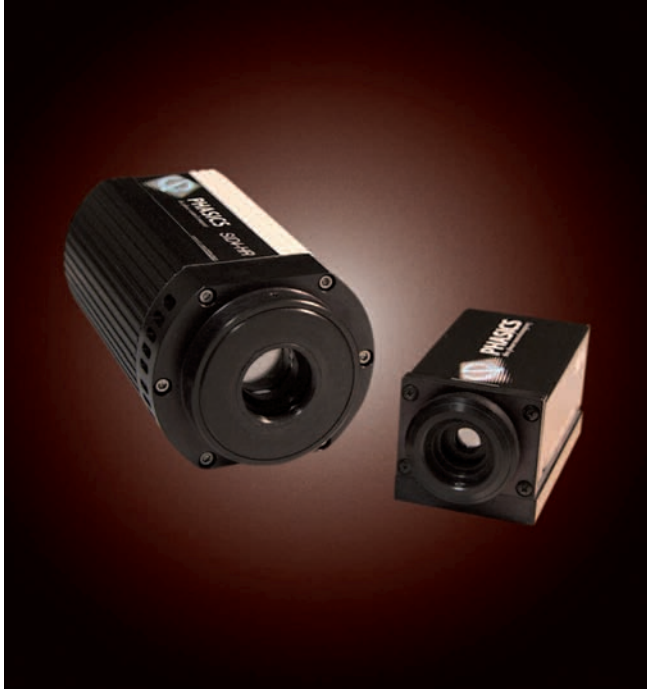


SID4



SID4



▼ KEY FEATURES

- High transverse resolution (160x120)
- Achromaticity
- Large spectral acceptance
- Intensity profile characterization (BeamView)
- Compact and versatile (controlled by laptop, "plug'n play")
- Multi-user, multi-device interface
- Easy to implement and user friendly software
- Various acquisition mode (real time, triggered, programmed acquisition...)

SID4 wave front sensor is an extremely compact device which combines classical interferometry advantages (sensitivity, high resolution & dynamic range measurement) with an easy implementation.

SID4 advantages come from the 4-Wave Lateral Shearing Interferometry* (based on the Modified Hartmann Mask Diffractive Optics) an innovative technology developed at ONERA for metrology needs.

"A REVOLUTION IN WAVE FRONT SENSING"

SID4 is an essential tool for laser beam characterization and find numerous applications in optical metrology.

PHASICS - The phase control company



WAVE FRONT SENSOR

↓ SPECIFICATIONS

Aperture dimension	3.6 x 4.8 mm ²
Spatial resolution	29.6 μm
Phase and intensity sampling	160 x 120 (> 19000 points)
Wavelength range	350 - 1100 nm
Accuracy (absolute/relative mode)	10 nm RMS / 3 nm RMS
Sensitivity	3 nm RMS
Dynamic	> 100 μm
Radius of curvature	20 mm (5 mm optional)
Curvature repeatability	5. 10 ⁻⁴ m ⁻¹
Numerical aperture	0.1NA f/5 (0.3 NA f/1.6 optional)
Analysis rate (full resolution)	> 10 fps
Acquisition rate	60 fps
Dimensions (l x H x L)	49 x 35 x 110 mm
Weight	250 g

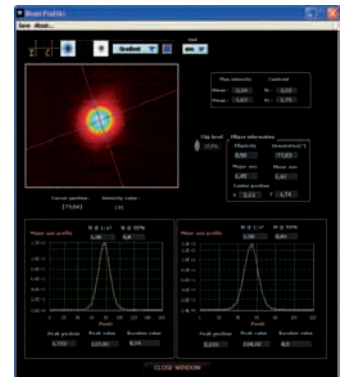
↓ SOFTWARE FEATURES

Phase map interpretation modules

- Tilt
- Divergence
- Zernike polynomials
- Legendre polynomials

Beam analysis

- Simultaneous phase and intensity maps
- M² calculation
- Strehl ratio
- Far-field analysis



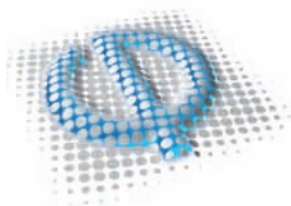
BeamView module window

Ergonomics

- Intuitive software
- Multi-user interface
- Automatic mask analysis adjustment

BeamView (option)

- Complete beam analysis
- Intensity profiles
- Gaussian fit



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